

October 1987 Revised May 2002

## CD4724BC 8-Bit Addressable Latch

#### **General Description**

The CD4724BC is an 8-bit addressable latch with three address inputs (A0–A2), an active low enable input  $(\overline{E}),$  active high clear input (C<sub>L</sub>), a data input (D) and eight outputs (Q0–Q7).

Data is entered into a particular bit in the latch when that is addressed by the address inputs and the enable  $(\overline{E})$  is LOW. Data entry is inhibited when enable  $(\overline{E})$  is HIGH.

When clear  $(C_L)$  and enable  $(\overline{E})$  are HIGH, all outputs are LOW. When clear  $(C_L)$  is HIGH and enable  $(\overline{E})$  is LOW, the channel demultiplexing occurs. The bit that is addressed has an active output which follows the data input while all unaddressed bits are held LOW. When operating in the addressable latch mode  $(\overline{E}=C_L=LOW)$ , changing more than one bit of the address could impose a transient wrong address. Therefore, this should only be done while in the memory mode  $(\overline{E}=HIGH,\,C_I=LOW)$ .

#### **Features**

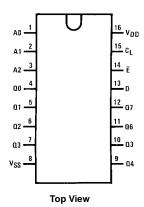
- Wide supply voltage range: 3.0V to 15V
- High noise immunity: 0.45 V<sub>DD</sub> (typ.)
- Low power TTL compatibility: fan out of 2 driving 74L or 1 driving 74LS
- Serial to parallel capability
- Storage register capability
- Random (addressable) data entry
- Active high demultiplexing capability
- Common active high clear

#### **Ordering Code:**

Order Number	Package Number	Package Description					
CD4724BCM	M16A	16-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow					
CD4724BCN	N16F	16-Lead Plastic Dual-In-Line Package (PDIP) JEDEC MS-001_0_300" Wide					

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code

#### **Connection Diagram**



#### **Truth Table**

	Mode Selection							
Ē	СГ	Addressed	Unaddressed	Mode				
		Latch	Latch					
L	L	Follows Data	Holds Previous Data	Addressable Latch				
Н	L	Hold Previous Data	Holds Previous Data	Memory				
L	Н	Follows Data	Reset to "0"	Demultiplexer				
Н	Н	Reset to "0"	Reset to "0"	Clear				

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### **Absolute Maximum Ratings**(Note 1)

(Note 2)

 $\begin{array}{ll} \text{DC Supply Voltage (V}_{DD}) & -0.5\text{V to } +18\text{ V}_{DC} \\ \text{Input Voltage (V}_{IN}) & -0.5\text{V to V}_{DD} +0.5\text{ V}_{DC} \\ \text{Storage Temperature (T}_{S}) & -65^{\circ}\text{C to } +150^{\circ}\text{C} \end{array}$ 

Power Dissipation (P<sub>D</sub>)

Dual-In-Line 700 mW Small Outline 500 mW

Lead Temperature (T<sub>L</sub>)

(Soldering, 10 seconds) 260°C

# Recommended Operating Conditions (Note 2)

DC Supply Voltage ( $V_{DD}$ ) 3.0V to 15  $V_{DC}$ Input Voltage ( $V_{IN}$ ) 0V to  $V_{DD}$   $V_{DC}$ Operating Temperature Range ( $T_A$ ) -55°C to +125°C

Note 1: "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed; they are not meant to imply that the devices should be operated at these limits. The tables of "Recommended Operating Conditions" and Electrical Characteristics" provide conditions for actual device operation.

Note 2:  $V_{SS} = 0V$  unless otherwise specified.

### DC Electrical Characteristics (Note 2)

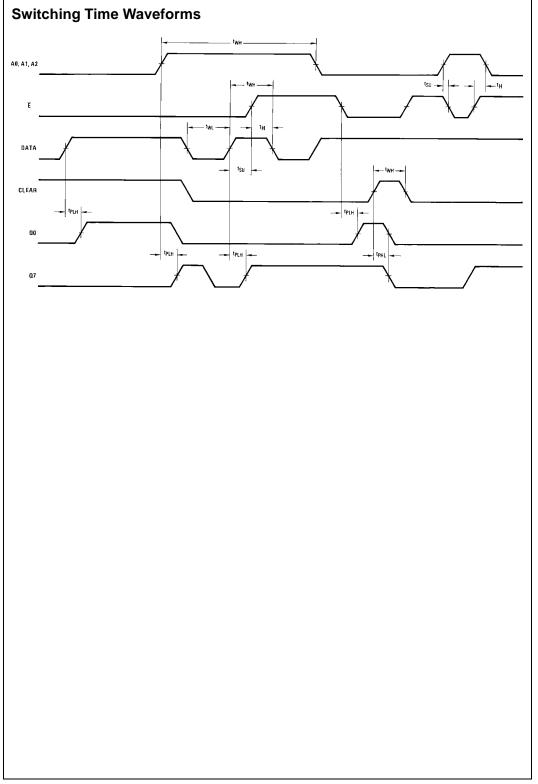
Symbol	Parameter	Conditions	–55°C		+25°C			+125°C		Units
Symbol	Parameter	Conditions	Min	Max	Min	Тур	Max	Min	Max	Oilles
I <sub>DD</sub>	Quiescent Device	$V_{DD} = 5V$		5		0.02	5		150	
	Current	V <sub>DD</sub> = 10V		10		0.02	10		300	μΑ
		V <sub>DD</sub> = 15V		20		0.02	20		600	
V <sub>OL</sub>	LOW Level	I <sub>O</sub>   ≤ 1 μA								
	Output Voltage	$V_{DD} = 5V$		0.05		0	0.05		0.05	
		V <sub>DD</sub> = 10V		0.05		0	0.05		0.05	V
		V <sub>DD</sub> = 15V		0.05		0	0.05		0.05	
V <sub>OH</sub>	HIGH Level	I <sub>O</sub>   ≤ 1 μA								
	Output Voltage	$V_{DD} = 5V$	4.95		4.95	5.0		4.95		
		V <sub>DD</sub> = 10V	9.95		9.95	10		9.95		V
		V <sub>DD</sub> = 15V	14.95		14.95	15		14.95		
V <sub>IL</sub>	LOW Level	$V_{DD} = 5V, V_{O} = 0.5V \text{ or } 4.5V$		1.5		2.25	1.5		1.5	
	Input Voltage	$V_{DD} = 10V, V_{O} = 1V \text{ or } 9V$		3.0		4.5	3.0		3.0	V
		$V_{DD} = 15V, V_{O} = 1.5V \text{ or } 13.5V$		4.0		6.75	4.0		4.0	
V <sub>IH</sub>	HIGH Level	$V_{DD} = 5V, V_{O} = 0.5V \text{ or } 4.5V$	3.5		3.5	2.75		3.5		
	Input Voltage	$V_{DD} = 10V, V_{O} = 1V \text{ or } 9V$	7.0		7.0	5.5		7.0		V
		$V_{DD} = 15V, V_{O} = 1.5V \text{ or } 13.5V$	11.0		11.0	8.25		11.0		
I <sub>OL</sub>	LOW Level Output	$V_{DD} = 5V, V_{O} = 0.4V$	0.64		0.51	0.88		0.36		
	Current	$V_{DD} = 10V, V_{O} = 0.5V$	1.6		1.3	2.25		0.9		mA
	(Note 3)	$V_{DD} = 15V, V_{O} = 1.5V$	4.2		3.4	8.8		2.4		
I <sub>OH</sub>	HIGH Level Output	$V_{DD} = 5V, V_{O} = 4.6V$	-0.64		-0.51	-0.88		-0.36		
	Current	$V_{DD} = 10V, V_{O} = 9.5V$	-1.6		-1.3	-2.25		-0.9		mA
	(Note 3)	$V_{DD} = 15V, V_{O} = 13.5V$	-4.2		-3.4	-8.8		-2.4		
I <sub>IN</sub>	Input Current	V <sub>DD</sub> = 15V, V <sub>IN</sub> = 0V		-0.1		-10 <sup>-5</sup>	-0.1		-1.0	μА
		V <sub>DD</sub> = 15V, V <sub>IN</sub> = 15V		0.1		10 <sup>-5</sup>	0.1		1.0	μА

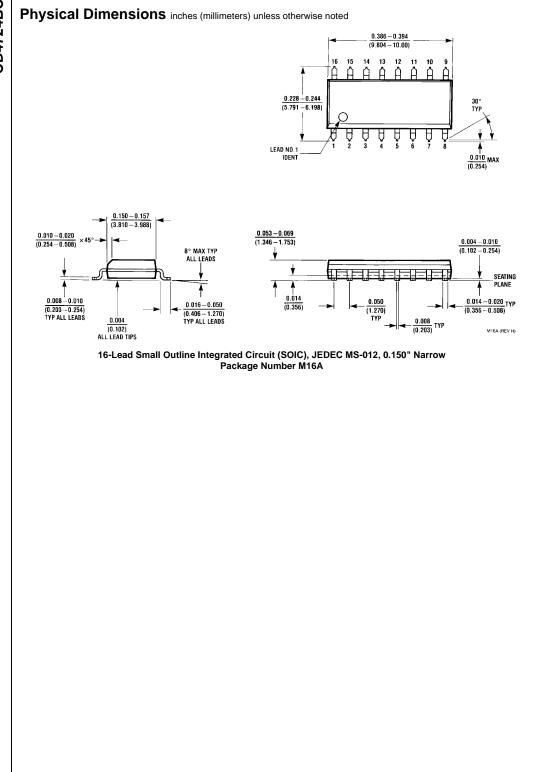
Note 3:  $I_{OL}$  and  $I_{OH}$  are tested one output at a time.

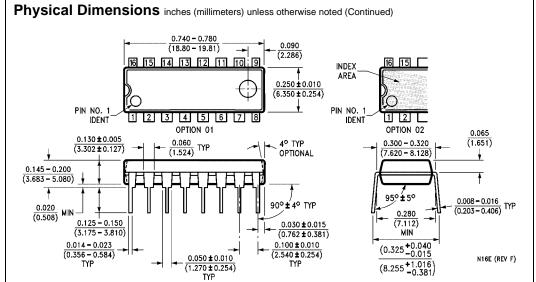
	$C_L = 50 \text{ pF}, R_L = 200 \text{k}, Input$					
Symbol	Parameter	Conditions	Min	Тур	Max	Uni
t <sub>PHL, tPLH</sub>	Propagation Delay	$V_{DD} = 5V$		200	400	1
	Data to Output	$V_{DD} = 10V$		75	150	n
		V <sub>DD</sub> = 15V		50	100	<u> </u>
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation Delay	$V_{DD} = 5V$		200	400	
	Enable to Output	$V_{DD} = 10V$		80	160	n
		$V_{DD} = 15V$		60	120	Í
t <sub>PHL</sub>	Propagation Delay	$V_{DD} = 5V$		175	350	
	Clear to Output	$V_{DD} = 10V$		80	160	n
		$V_{DD} = 15V$		65	130	1
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation Delay	$V_{DD} = 5V$		225	450	
	Address to Output	$V_{DD} = 10V$		100	200	n
		V <sub>DD</sub> = 15V		75	150	1
t <sub>THL</sub> , t <sub>TLH</sub>	Transition Time	$V_{DD} = 5V$		100	200	
	(Any Output)	$V_{DD} = 10V$		50	100	n
		V <sub>DD</sub> = 15V		40	80	1
T <sub>WH</sub> , T <sub>WL</sub>	Minimum Data	$V_{DD} = 5V$		100	200	
	Pulse Width	V <sub>DD</sub> = 10V		50	100	n
		V <sub>DD</sub> = 15V		40	80	1
t <sub>WH</sub> , t <sub>WL</sub>	Minimum Address	V <sub>DD</sub> = 5V	+	200	400	
	Pulse Width	V <sub>DD</sub> = 10V		100	200	n
		V <sub>DD</sub> = 15V		65	125	1
t <sub>WH</sub>	Minimum Clear	V <sub>DD</sub> = 5V		75	150	
****	Pulse Width	V <sub>DD</sub> = 10V		40	75	n
		V <sub>DD</sub> = 15V		25	50	1
t <sub>SU</sub>	Minimum Setup Time	V <sub>DD</sub> = 5V	+	40	80	
30	Data to E	$V_{DD} = 10V$		20	40	n
		V <sub>DD</sub> = 15V		15	30	1
t <sub>H</sub>	Minimum Hold Time	V <sub>DD</sub> = 5V	-	60	120	<b> </b>
П	Data to E	$V_{DD} = 10V$		30	60	n
		V <sub>DD</sub> = 15V		25	50	1
t <sub>SU</sub>	Minimum Setup Time	V <sub>DD</sub> = 5V	_	-15	50	<b> </b>
*50	Address to E	$V_{DD} = 10V$		0	30	n
	/ tudioso to E	$V_{DD} = 15V$		0	20	1
t <sub>H</sub>	Minimum Hold Time	$V_{DD} = 5V$	+	-50	15	<del>                                     </del>
ч	Address to E	$V_{DD} = 3V$ $V_{DD} = 10V$		-20	10	n
	Address to E	$V_{DD} = 15V$		- <u>1</u> 5	5	1
C <sub>PD</sub>	Power Dissipation	Per Package		100	لـــنّـــا	р
CPD	Capacitance	(Note 5)		100	1 '	
C <sub>IN</sub>	Input Capacitance	Any Input		5.0	7.5	р

Note 4: AC Parameters are guaranteed by DC correlated testing.

Note 5: Dynamic power dissipation ( $P_D$ ) is given by:  $P_D = (C_{PD} + C_L) \ V_{CC}^2 f + P_Q$ ; where  $C_L = load$  capacitance; f = f frequency of operation; for further details, see Application Note AN-90, "Family Characteristics".







16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide Package Number N16E

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